

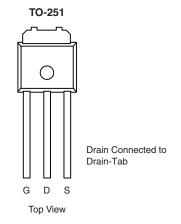
N-Channel 100-V (D-S) MOSFET

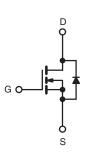
PRODUCT SUMMARY					
V _{DS} (V)	100				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 0.20				
Q _g (Max.) (nC)	16				
Q _{gs} (nC)	4.4				
Q _{gd} (nC)	7.7				
Configuration	Single				

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T_{C}	= 25 °C, unl	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	100	V	
Gate-Source Voltage			V_{GS}	± 20	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$	T _C = 25 °C	I _D	12		
Continuous Drain Current		T _C = 100 °C		7.5	Α	
Pulsed Drain Current ^a			I _{DM}	37		
Linear Derating Factor				0.40	W/°C	
Linear Derating Factor (PCB Mount)				0.025	\ \\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	
Single Pulse Avalanche Energy ^b			E _{AS}	200	mJ	
Avalanche Currenta			I _{AR}	9.2	Α	
Repetitive Avalanche Energy ^a			E _{AR}	6.0	mJ	
Maximum Power Dissipation	T _C =	T _C = 25 °C		60	w	
Maximum Power Dissipation (PCB Mount)	T _A = 25 °C		P_{D}	3.7		
Peak Diode Recovery dV/dt ^c			dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	***	
Soldering Recommendations (Peak Temperature)	re) For 10 s		, and the second	300 ^d	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=25$ V, starting $T_J=25$ °C, L=3.5 mH, $R_q=25$ Ω , $I_{AS}=9.2$ A (see fig. 12). c. $I_{SD}\leq 9.2$ A, $dI/dt\leq 110$ A/µs, $V_{DD}\leq V_{DS}$, $T_J\leq 175$ °C.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	40	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0, I _D = 250 μA	100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.13	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	· V _{GS} , I _D = 250 μA	1.0	-	3.0	V
Gate-Source Leakage	I _{GSS}	,	$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zawa Cata Valtana Busin Comment		V _{DS} =	V _{DS} = 100 V, V _{GS} = 0 V		-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V	V _{GS} = 0 V, T _J = 150 °C	-	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 5.5 A ^b	-	0.20	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 5.5 A ^b	2.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	360	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 V$,	-	150	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.	0 MHz, see fig. 5	-	34	-	
Total Gate Charge	Qg			-	-	16	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_D = 9.2 \text{ A, } V_{DS} = 80 \text{ V,}$ see fig. 6 and 13 ^b		-	4.4	nC
Gate-Drain Charge	Q _{gd}				-	7.7	
Turn-On Delay Time	t _{d(on)}			-	8.8	-	ne
Rise Time	t _r	V _{DD} =	= 50 V, I _D = 9.2 A,	-	30	-	
Turn-Off Delay Time	t _{d(off)}	$R_g = 18 \Omega$, $R_D = 5.2 \Omega$, see fig. 10^b		-	19	-	ns -
Fall Time	t _f			-	20	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH
Internal Source Inductance	L _S			-	7.5	-	'"'
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	9.2	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	37	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 9.2 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T 25 °C 1	- 0.2 A dl/dt = 100 A/	-	110	260	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 9.2 \text{A}, dI/dt = 100 \text{A}/\mu\text{s}^b$		-	0.53	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	on is dor	ninated b	y L _S and	L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

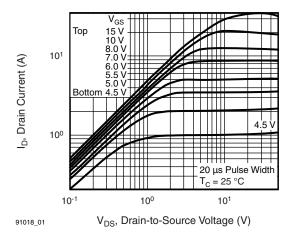


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

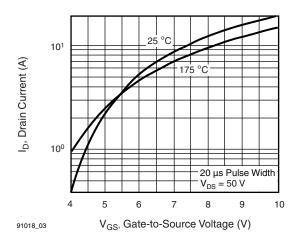


Fig. 3 - Typical Transfer Characteristics

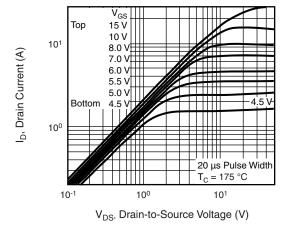


Fig. 2 - Typical Output Characteristics, T_C = 175 $^{\circ}C$

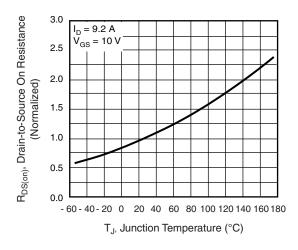
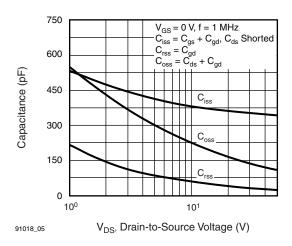
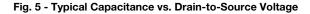


Fig. 4 - Normalized On-Resistance vs. Temperature

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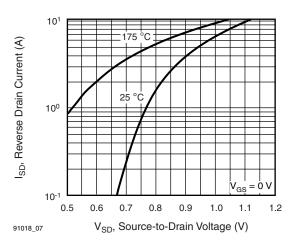


Fig. 7 - Typical Source-Drain Diode Forward Voltage

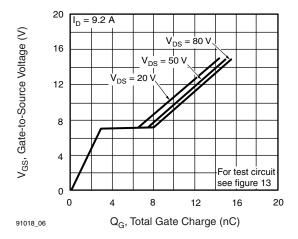


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

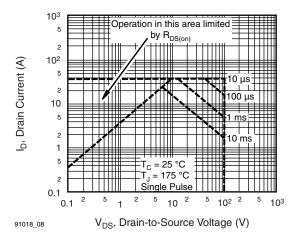


Fig. 8 - Maximum Safe Operating Area



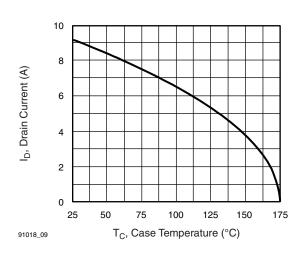


Fig. 9 - Maximum Drain Current vs. Case Temperature

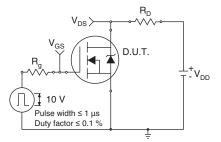


Fig. 10a - Switching Time Test Circuit

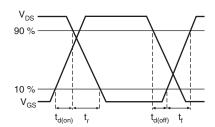


Fig. 10b - Switching Time Waveforms

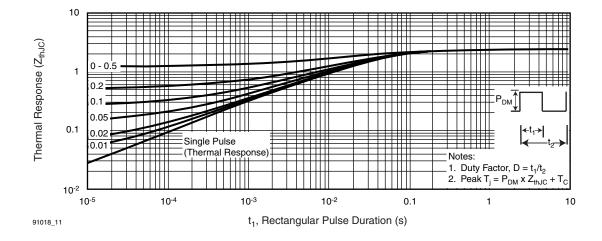


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



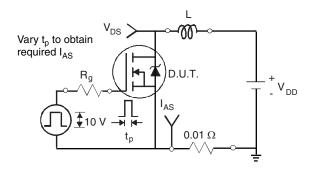


Fig. 12a - Unclamped Inductive Test Circuit

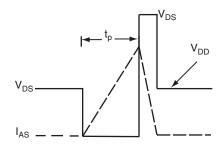


Fig. 12b - Unclamped Inductive Waveforms

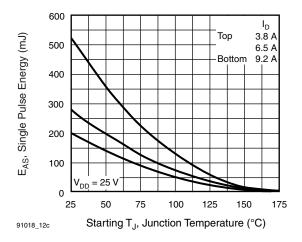


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

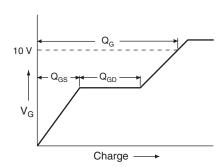


Fig. 13a - Basic Gate Charge Waveform

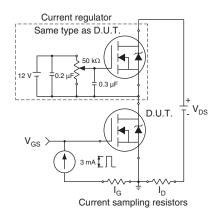
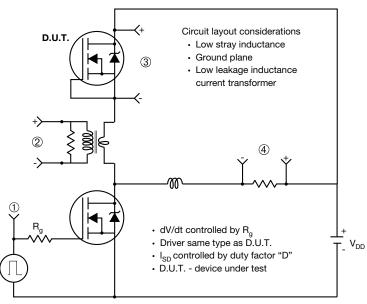


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



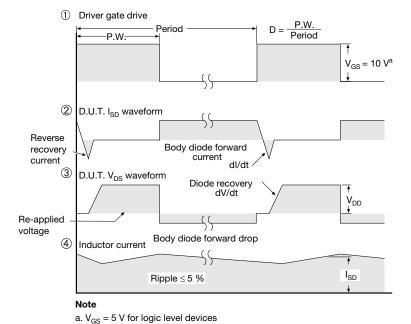
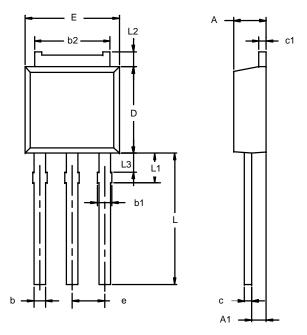


Fig. 14 - For N-Channel



TO-251AA



Note:	Dimension	I 3 is f	or refer	ence only
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	MILLIM	IETERS	INC	HES
Dim	Min	Max	Min	Max
Α	2.21	2.38	0.087	0.094
A1	0.89	1.14	0.035	0.045
b	0.71	0.89	0.028	0.035
b1	0.76	1.14	0.030	0.045
b2	5.23	5.43	0.206	0.214
С	0.46	0.58	0.018	0.023
с1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
Е	6.48	6.73	0.255	0.265
е	2.28 BSC		0.090 BSC	
L	3.89	9.53	0.153	0.375
L1	1.91	2.28	0.075	0.090
L2	0.89	1.27	0.035	0.050
L3	1.15	1.52	0.045	0.060



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